JEOL 7600F: Analytical High Resolution SEM

Main imaging capabilities
- High resolution: 1.0 nm at 15 keV
  1.5 nm at 1 kV
  5.0 nm at 0.1 kV
- STEM imaging: 0.8 nm at 30 kV
- Probe current: 0.1 pA to 200 nA
- Low Angle Backscattered Electron Detector (LABe):
  - Hi-res backscattered electron (BSE) imaging at low energies.

X-ray analysis capabilities
- Energy dispersive spectrometer:
  80 mm² silicon drift detector
  (129 eV resolution)
- Wavelength dispersive spectrometer:
  Five diffracting crystals to analyze down to Be (Z=4)

Miscellaneous
- Alicona MeX software package for surface metrology using SEM stereoscopic images

Sample courtesy of Y. Zhang (CFN)

Sample courtesy of D. Nykypanchuk (CFN)